

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination 10/716,748 POLCAWICH ET AL.	
		Examiner	Art Unit	Page 1 of 1 Sang Nguyen

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,870,626	03-2005	Autrey et al.	356/432
*	B	US-6,608,683	08-2003	Pilgrim et al.	356/432
*	C	US-6,600,558	07-2003	Ueno et al.	356/246
*	D	US-6,348,968	02-2002	Autrey et al.	356/432
*	E	US-6,344,647	02-2002	Jourdain et al.	250/339.07
*	F	US-6,286,360	09-2001	Drzewiecki, Tadeusz M.	73/24.01
*	G	US-6,244,101	06-2001	Autrey et al.	73/61.45
*	H	US-6,188,474	02-2001	Dussault et al.	356/246
*	I	US-5,110,727	05-1992	Oberhardt, Bruce J.	435/13
*	J	US-4,096,626	06-1978	Olsen et al.	29/846
*	K	US-4,761,381	08-1988	Blatt et al.	436/165
*	L	US-4,028,932	06-1977	Rosencwaig, Allan	73/579
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.